Octal D-Type Flip-Flop with 3-State Outputs

The MC74LVX574 is an advanced high speed CMOS octal flip–flop with 3–state outputs. The inputs tolerate voltages up to 7V, allowing the interface of 5V systems to 3V systems.

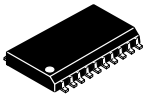
This 8–bit D–type flip–flop is controlled by a clock pulse input and an output enable input. When the output enable input is high, the eight outputs are in a high impedance state.

- High Speed: t_{PD} = 8.5ns (Typ) at V_{CC} = 3.3V
- Low Power Dissipation: I_{CC} = 4μA (Max) at T_A = 25°C
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Low Noise: V_{OLP} = 0.8V (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300mA
- ESD Performance: HBM > 2000V; Machine Model > 200V

MC74LVX574

LVX

LOW–VOLTAGE CMOS



DW SUFFIX
20–LEAD SOIC PACKAGE
CASE 751D–04

DT SUFFIX
20–LEAD TSSOP PACKAGE
CASE 948E–02

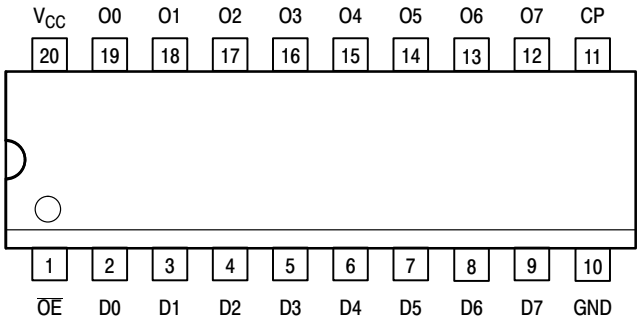


Figure 1. 20–Lead Pinout (Top View)

PIN NAMES

Pins	Function
$\overline{OE}$	Output Enable Input
CP	Clock Pulse Input
D0–D7	Data Inputs
O0–O7	3–State Latch Outputs

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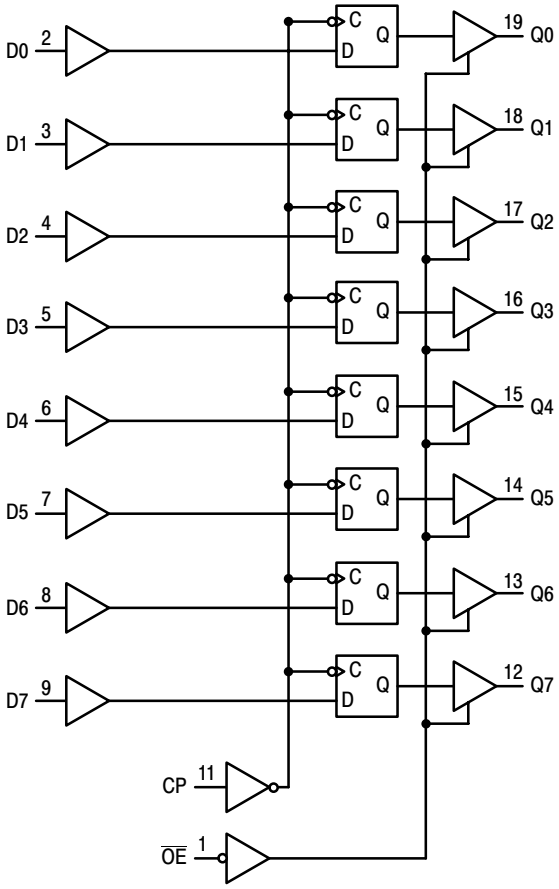


Figure 2. Logic Diagram

FUNCTION TABLE

INPUTS			OUTPUT
$\overline{OE}$	CP	D	Q
L	↑	H	H
L	↑	L	L
L	L, H, ↓	X	No Change
H	X	X	Z

MAXIMUM RATINGS*

Symbol	Parameter	Value	Unit
V_{CC}	DC Supply Voltage	–0.5 to +7.0	V
V_{in}	DC Input Voltage	–0.5 to +7.0	V
V_{out}	DC Output Voltage	–0.5 to V_{CC} +0.5	V
I_{IK}	Input Diode Current	–20	mA
I_{OK}	Output Diode Current	±20	mA
I_{out}	DC Output Current, per Pin	±25	mA
I_{CC}	DC Supply Current, V_{CC} and GND Pins	±75	mA
P_D	Power Dissipation	180	mW
T_{stg}	Storage Temperature	–65 to +150	°C

* Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute–maximum–rated conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V_{CC}	DC Supply Voltage	2.0	3.6	V
V_{in}	DC Input Voltage	0	5.5	V
V_{out}	DC Output Voltage	0	V_{CC}	V
T_A	Operating Temperature, All Package Types	–40	+85	°C
$\Delta t/\Delta V$	Input Rise and Fall Time	0	100	ns/V

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test Conditions	V_{CC} V	T_A = 25°C			T_A = – 40 to 85°C		Unit
				Min	Typ	Max	Min	Max	
V_{IH}	High–Level Input Voltage		2.0 3.0 3.6	1.5 2.0 2.4			1.5 2.0 2.4		V
V_{IL}	Low–Level Input Voltage		2.0 3.0 3.6			0.5 0.8 0.8		0.5 0.8 0.8	V
V_{OH}	High–Level Output Voltage (V_{in} = V_{IH} or V_{IL})	I_{OH} = –50μA I_{OH} = –50μA I_{OH} = –4mA	2.0 3.0 3.0	1.9 2.9 2.58	2.0 3.0		1.9 2.9 2.48		V
V_{OL}	Low–Level Output Voltage (V_{in} = V_{IH} or V_{IL})	I_{OL} = 50μA I_{OL} = 50μA I_{OL} = 4mA	2.0 3.0 3.0		0.0 0.0	0.1 0.1 0.36		0.1 0.1 0.44	V
I_{in}	Input Leakage Current	V_{in} = 5.5V or GND	3.6			±0.1		±1.0	μA
I_{OZ}	Maximum Three–State Leakage Current	V_{in} = V_{IL} or V_{IH} V_{out} = V_{CC} or GND	3.6			±0.25		±2.5	μA
I_{CC}	Quiescent Supply Current	V_{in} = V_{CC} or GND	3.6			4.0		40.0	μA

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0$ns)

Symbol	Parameter	Test Conditions	$T_A = 25°C$ Min	$T_A = 25°C$ Typ	$T_A = 25°C$ Max	$T_A = -40$ to $85°C$ Min	$T_A = -40$ to $85°C$ Max	Unit
f_{max}	Maximum Clock Frequency (50% Duty Cycle)	V_{CC} = 2.7V C_L = 15pF	60	115		50		ns
		V_{CC} = 2.7V C_L = 50pF	45	60		40		
		V_{CC} = 3.3 ± 0.3V C_L = 15pF	80	125		65		
		V_{CC} = 3.3 ± 0.3V C_L = 50pF	50	75		45		
t_{PLH}, t_{PHL}	Propagation Delay CP to O	V_{CC} = 2.7V C_L = 15pF		9.2	14.5	1.0	17.5	ns
		V_{CC} = 2.7V C_L = 50pF		11.5	18.0	1.0	21.0	
		V_{CC} = 3.3 ± 0.3V C_L = 15pF		8.5	13.2	1.0	15.5	
		V_{CC} = 3.3 ± 0.3V C_L = 50pF		11.0	16.7	1.0	19.0	
t_{PZL}, t_{PZH}	Output Enable Time $\overline{OE}$ to O	V_{CC} = 2.7V C_L = 15pF R_L = 1kΩ		9.8	15.0	1.0	18.5	ns
		V_{CC} = 2.7V C_L = 50pF R_L = 1kΩ		11.4	18.5	1.0	22.0	
		V_{CC} = 3.3 ± 0.3V C_L = 15pF R_L = 1kΩ		8.2	12.8	1.0	15.0	
		V_{CC} = 3.3 ± 0.3V C_L = 50pF R_L = 1kΩ		10.7	16.3	1.0	18.5	
t_{PLZ}, t_{PHZ}	Output Disable Time $\overline{OE}$ to O	V_{CC} = 2.7V C_L = 50pF R_L = 1kΩ		12.1	19.1	1.0	22.0	ns
		V_{CC} = 3.3 ± 0.3V C_L = 50pF R_L = 1kΩ		11.0	15.0	1.0	17.0	
t_{OSHL} t_{OSLH}	Output–to–Output Skew (Note NO TAG)	V_{CC} = 2.7V C_L = 50pF			1.5		1.5	ns
		V_{CC} = 3.3 ±0.3V C_L = 50pF			1.5		1.5	

1. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH–to–LOW (t_{OSHL}) or LOW–to–HIGH (t_{OSLH}); parameter guaranteed by design.

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	$T_A = 25°C$ Min	$T_A = 25°C$ Typ	$T_A = 25°C$ Max	$T_A = -40$ to $85°C$ Min	$T_A = -40$ to $85°C$ Max	Unit
C_{in}	Input Capacitance		4	10		10	pF
C_{out}	Maximum Three–State Output Capacitance		6				pF
C_{PD}	Power Dissipation Capacitance (Note 2)		28				pF

2. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \bullet V_{CC} \bullet f_{in} + I_{CC}/8$ (per latch). C_{PD} is used to determine the no–load dynamic power consumption; $P_D = C_{PD} \bullet V_{CC}^2 \bullet f_{in} + I_{CC} \bullet V_{CC}$.

NOISE CHARACTERISTICS (Input $t_r = t_f = 3.0$ns, $C_L = 50$pF, $V_{CC} = 3.3$V, Measured in SOIC Package)

Symbol	Characteristic	$T_A = 25°C$ Typ	$T_A = 25°C$ Max	Unit
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	0.5	0.8	V
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	–0.5	–0.8	V
V_{IHD}	Minimum High Level Dynamic Input Voltage		2.0	V
V_{ILD}	Maximum Low Level Dynamic Input Voltage		0.8	V

TIMING REQUIREMENTS (Input $t_r = t_f = 3.0$ns)

Symbol	Parameter	Test Conditions	T_A = 25°C		T_A = – 40 to 85°C	Unit
			Typ	Limit	Limit	
$t_{w(h)}$	Minimum Pulse Width, CP	V_{CC} = 2.7V V_{CC} = 3.3 ±0.3V		6.5 5.0	7.5 5.0	ns
t_{su}	Minimum Setup Time, D to CP	V_{CC} = 2.7V V_{CC} = 3.3 ±0.3V		5.0 3.5	5.0 3.5	ns
t_h	Minimum Hold Time, D to CP	V_{CC} = 2.7V V_{CC} = 3.3 ±0.3V		1.5 1.5	1.5 1.5	ns

SWITCHING WAVEFORMS

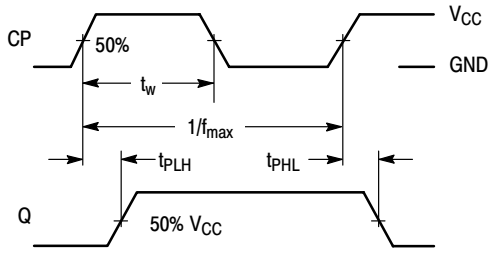


Figure 3.

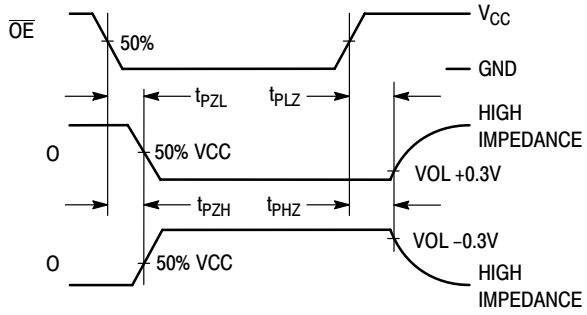


Figure 4.

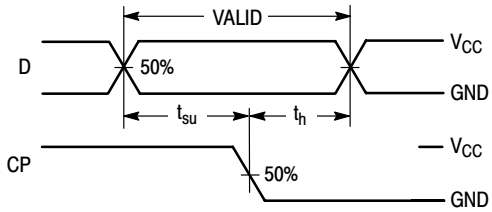
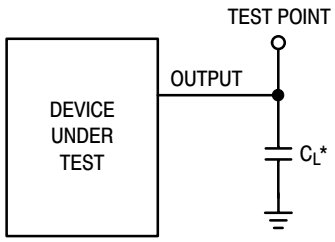


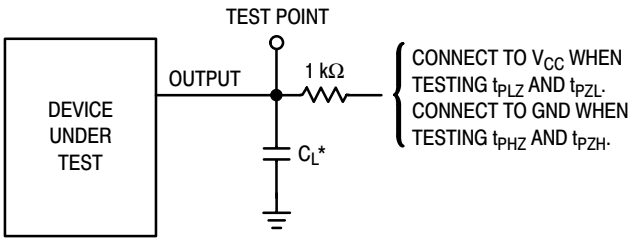
Figure 5.

TEST CIRCUITS



*Includes all probe and jig capacitance

Figure 6. Propagation Delay Test Circuit

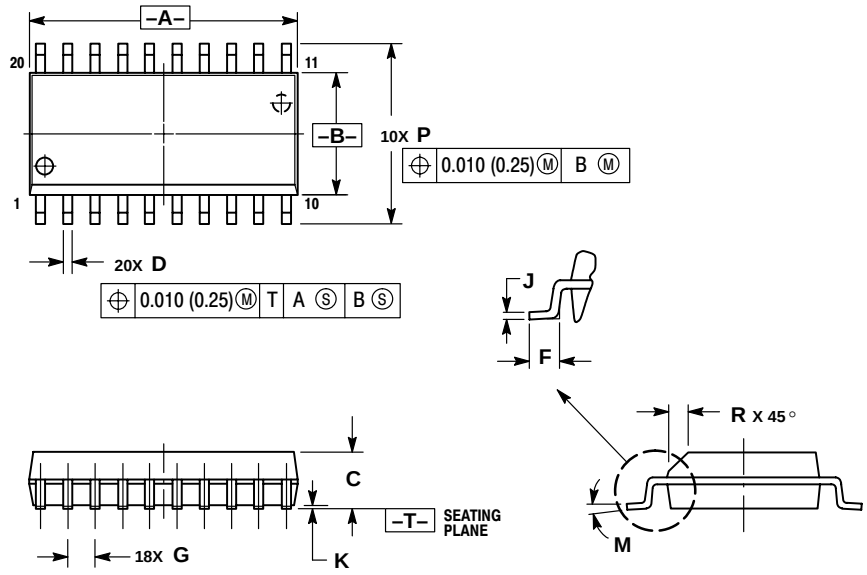


*Includes all probe and jig capacitance

Figure 7. Three–State Test Circuit

OUTLINE DIMENSIONS

DW SUFFIX
PLASTIC SOIC PACKAGE
CASE 751D–04
ISSUE E

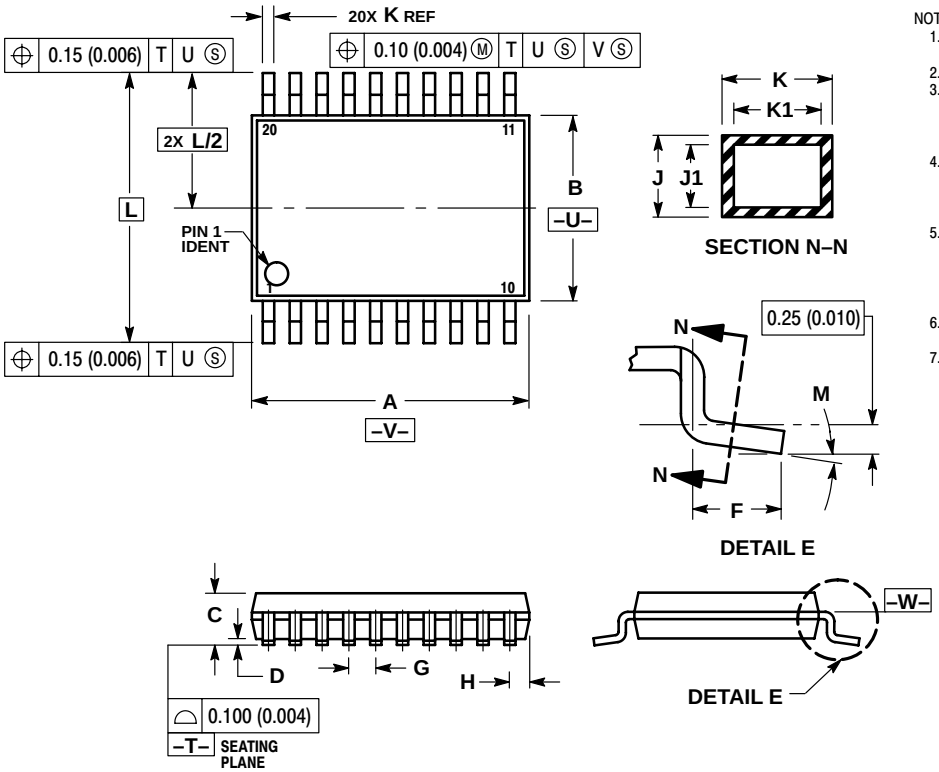


NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.150 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.13 (0.005) TOTAL IN EXCESS OF D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	12.65	12.95	0.499	0.510
B	7.40	7.60	0.292	0.299
C	2.35	2.65	0.093	0.104
D	0.35	0.49	0.014	0.019
F	0.50	0.90	0.020	0.035
G	1.27 BSC		0.050 BSC	
J	0.25	0.32	0.010	0.012
K	0.10	0.25	0.004	0.009
M	0 °	7 °	0 °	7 °
P	10.05	10.55	0.395	0.415
R	0.25	0.75	0.010	0.029

OUTLINE DIMENSIONS

DT SUFFIX
PLASTIC TSSOP PACKAGE
CASE 948E–02
ISSUE A



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE –W–.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	6.40	6.60	0.252	0.260
B	4.30	4.50	0.169	0.177
C	---	1.20	---	0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
H	0.27	0.37	0.011	0.015
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
M	0°	8°	0°	8°

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